

of a plurality of connection terminals and a single wiring pattern, each of said pin sockets connecting the wiring pattern to the connection terminal when a pin is inserted therein.

9. (Amended) An inspection apparatus for inspecting a plurality of semiconductor integrated circuits mounted on a base board, wherein the base board comprises:

a plurality of connection terminals electrically connected to terminals of an inspection main unit;

a plurality of wiring patterns connected to terminals of a semiconductor integrated circuit; and

a junction unit for changing the state of a junction formed between the connection terminals and the wiring pattern, wherein the junction unit includes an element mount pattern for connecting the wiring pattern to the connection terminals when a short-circuit element is mounted on the element mount pattern, and the element mount pattern is provided between each of a plurality of wiring patterns and a single connection terminal and/or between each of a plurality of connection terminals and a single wiring pattern.

10. (Amended) An inspection apparatus for inspecting a plurality of semiconductor integrated circuits mounted on a base board, wherein the base board comprises:

a plurality of connection terminals electrically connected to terminals of an inspection main unit;

a plurality of wiring patterns connected to terminals of a semiconductor integrated circuit; and